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What is claimed is:

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1. A method for optically inspecting a sample, the method comprising: illuminating the sample with an incident field;

measuring the resulting output field to determine an optical response of the sample;

generating measurement parameters that correspond to the measured optical response by performing the following operations:

- a) searching a database to locate a pre-computed optical response and associated measurement parameters,
- b) interpolating between pre-computed responses in the database to generate an interpolated optical response and associated measurement parameters, and
- c) iteratively evaluating a theoretical model to generate a theoretical optical response and associated measurement parameters.
- 2. A method as recited in claim 1 that further comprises the step of iteratively evaluating the theoretical model to generate the database.
- 20 3. A method as recited in claim 1 wherein the step of interpolating is performed without evaluating the theoretical model.
 - 4. A method as recited in claim 1 wherein the database searching, database interpolation and model evaluation operations are performed in sequence to successively refine an optical response and associated measurement parameters.
 - 5. A method as recited in claim 1 wherein the database interpolation is performed using reduced multicubic interpolation.
- 30 6. A method as recited in claim 1 wherein the operations a, b and c are performed in order.

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7.	A device for optically inspecting a sample, the device comprising:
a me	asurement system for illuminating the sample with an incident field and
measuring tl	he resulting output field to determine an optical response of the sample;
a pro	ocessor for generating measurement parameters that correspond to the
measured optical response, the processor configured to include:	

a database searching module for searching a database to locate a precomputed optical response and associated measurement parameters

a interpolated refinement module for interpolating between pre-computed responses in the database to generate an interpolated optical response and associated measurement parameters; and

a theoretical refinement module for iteratively evaluating a theoretical model to generate a theoretical optical response and associated measurement parameters.

- 8. A device as recited in claim 7 wherein the database is generated by iteratively evaluating the theoretical model.
 - 9. A device as recited in claim 7 wherein the interpolated refinement module operates without evaluating the theoretical model.

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10. A device as recited in claim 7 wherein the database searching, database interpolation and model evaluation operations are invoke in sequence to successively refine an optical response and associated measurement parameters.

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11. A device as recited in claim 7 wherein the database interpolation is performed using reduced multicubic interpolation.

illuminating the sample with an incident field;

measuring the resulting output field to determine a measured optical response of the sample;

searching within a database of pre-computed optical responses and associated measurement parameters to locate the pre-computed optical response that most closely matches the measured optical response;

interpolating within the database to refine the pre-computed optical response obtained from the database to more closely match the measured optical response; and iteratively evaluating a theoretical model to refine the optical response obtained by interpolation to more closely match the measured optical response.

- 12. A method as recited in claim 11 that further comprises the step of iteratively evaluating the theoretical model to generate the database.
 - 13. A method as recited in claim 11 wherein the step of interpolating is performed without evaluating the theoretical model.
- 20 14. A method as recited in claim 11 wherein the database interpolation is performed using reduced multicubic interpolation.
 - 15. A method of evaluating a sample comprising the steps of: creating a database of pre-computed optical responses and associated measurement parameters of the sample;

optically inspecting the sample to generate an empirical optical response; comparing the empirical optical response to the theoretical optical responses stored in the database and selecting the closest match;

using the closest match, interpolating between pre-computed responses in the
database to generate an interpolated optical response and associated measurement
parameters; and

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using the interpolated optical response and associated measurement parameters as a starting point, iteratively evaluating a theoretical model corresponding to the sample to minimize the difference between theoretically generated optical responses and the empirical optical response to produce a best fit for the actual measurement parameters of the sample.

- 16. A method as recited in claim 15 that further comprises the step of iteratively evaluating the theoretical model to generate the database.
- 10 17. A method as recited in claim 15 wherein the interpolated optical response is generated without evaluating the theoretical model.
 - 18. A method as recited in claim 15 wherein the interpolated optical response is generated using reduced multicubic interpolation.

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